

Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/649,918	OKA ET AL.
Examiner	Art Unit
Syed Zaidi	2616

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	10/15/2007	SZ
Inventor : Oka et all	10/15/2007	SZ
IEEE Xplore Database(http://ieeexplore.ieee.org/Xplore/DynWel.jsp)	10/15/2007	SZ
(370/328 370/329 370/330 370/331 370/338).CCLS.	10/15/2007	SZ
Consulted with SPE Seema S.Rao	10/15/2007	SZ